

HASO EUV

Wavefront sensor
The Hartmann

From EUV to soft X-Ray Achromatic technology Vacuum compatible







Imagine Optic's HASO
EUV wavefront sensor
was developed in
collaboration with LOA
laboratory and the
SOLEIL synchrotron.

It is the only device of its kind that offers you the extreme precision and direct measurement functionality needed for today's most demanding laboratory and industrial applications.

APPLICATIONS

Designed and built in collaboration with our customers to meet their needs, the HASO EUV performs multiple functions.

With it you can:

- + Align and characterize Synchrotron, EUV-FEL and laser-driven secondary source
- + Do micro- and nano-focusing
- + Diagnose dense plasma
- + Align automatically EUV optical systems
- + Make EUV lithography
- + Analyze gas or solid high-harmonic generation

FEATURES

- + Compatible with coherent and non-coherent sources
- + Usable for closed- and open-loop adaptive optics
- + Patented rotated square technology offering high resolution and wide dynamic range
- + Suitable for mono- and polychromatic beams
- + Hydrocarbon free and compatible with 10⁻⁷ mbar



SPECIFICATIONS*

OPERATING SPECS

Aperture dimension Number of sub-apertures dedicated for analysis Minimum readout time Working photon energy (Wavelenght range) Operating system

OPTICAL SPECS

Repeatability

Wavefront measurement accuracy

- In absolute mode
- In relative mode
 Spatial sampling

Tilt measurment sensitivity Focus dynamic range Numerical aperture

MISC

Dimensions (Height x Width x Length) Weight Sensor type Working temperature Compliant vacuum (hydrocarbon free)

Interface

Power consumption

*Subject to changes without further notice /!\ Acquisition & processing frequencies depend on computer

Standard EUV

13 x 13 mm² 72 x 72

~ 600 ms (2MHz digitalization) 30-300 eV (4-40 nm) Windows 10 & 11

- ~ λ/200 RMS
- \sim λ /50 RMS @ 13.5 nm
- ~ λ/100 RMS @ 13.5 nm
- ~ 180 µm 0.05 µrad RMS ± 0.5 m to ± ∞ 0.013

Ø 115 mm, L 270 mm

8 Kg

Vacuum interface 15-30 °C 10⁻⁷ mbar USB 2.0 12 VDC

High NA EUV

22.5 x 22.5 mm² 130 x 130 21 µs to 10 s 30-300 eV (4-40 nm) Windows 10 & 11

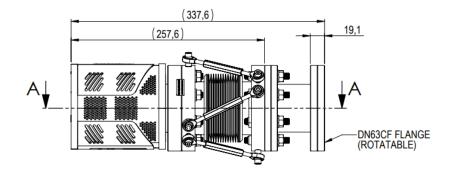
- ~ 1/200 RMS
- < \(\cdot 20 \) RMS @ 10 nm
- < \lambda/40 ~ 170 \mum 0.1 \murad RMS ± 0.45 m to ± ∞
- 0.15

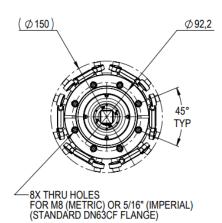
276 x 102 x 114 mm³ 3.3 Kg In vacuum 15-30 °C 5x10⁻⁷ mbar

USB 3.0 60 W @ 12 VDC



DIMENSIONS (mm)





SOFTWARE

WAVEVIEW™ Metrology Software

WAVEVIEW[™] is the most advanced wavefront measurement and analysis software.

It offers more than 150 features and tools optimized for a wide range of highly demanding applications.

Options:

- + Extensions for PSF, MTF, M², Strehl ratio and advanced Zernike
- + Optional SDK in C, LabVIEW and Python



CONTACT US

18, rue Charles de Gaulle 91400 ORSAY · France Phone +33 (0)1 64 86 15 60 sales@imagine-optic.com www.imagine-optic.com

